Search	Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/750,252	HAN, CHANG HUN
Examiner	Art Unit
Richard A. Booth	2812

	SEAR	CHED	
Class	Subclass	Date	Examiner
438	257-267	2/28/2005	RAB
438	593-594	2/28/2005	RAB
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
	·			

SEARCH I (INCLUDING SEAR	NOTES CH STRATEGY	<u>′) </u>
	DATE	EXMR